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**Sinsheimer et al.**

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(54) **X-RAY FILTER FOR X-RAY POWDER  
DIFFRACTION**

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CPC ..... **G21K 1/10** (2013.01); **G01N 23/20008**  
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A61B 6/00; A61B 6/4042; G01N 23/207  
See application file for complete search history.

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This patent is subject to a terminal dis-  
claimer.

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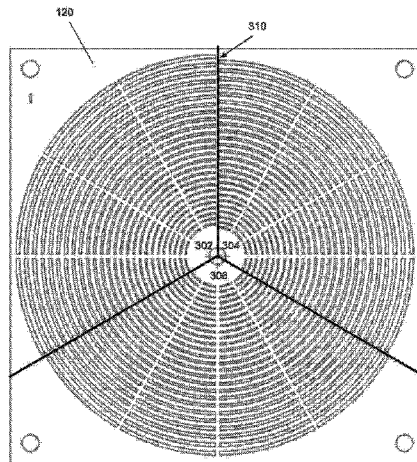
(63) Continuation of application No. 14/955,404, filed on  
Dec. 1, 2015, now Pat. No. 9,875,821.

(60) Provisional application No. 62/085,870, filed on Dec.  
1, 2014.

(51) **Int. Cl.**  
**G01N 23/203** (2006.01)  
**A61B 6/03** (2006.01)

(57) **ABSTRACT**  
  
Technologies are described for apparatus, methods and  
systems effective for filtering. The filters may comprise a  
first plate. The first plate may include an x-ray absorbing  
material and walls defining first slits. The first slits may  
include arc shaped openings through the first plate. The  
walls of the first plate may be configured to absorb at least  
some of first x-rays when the first x-rays are incident on the  
x-ray absorbing material, and to output second x-rays. The  
filters may comprise a second plate spaced from the first  
plate. The second plate may include the x-ray absorbing  
material and walls defining second slits. The second slits  
may include arc shaped openings through the second plate.  
The walls of the second plate may be configured to absorb  
at least some of second x-rays and to output third x-rays.

**3 Claims, 9 Drawing Sheets**



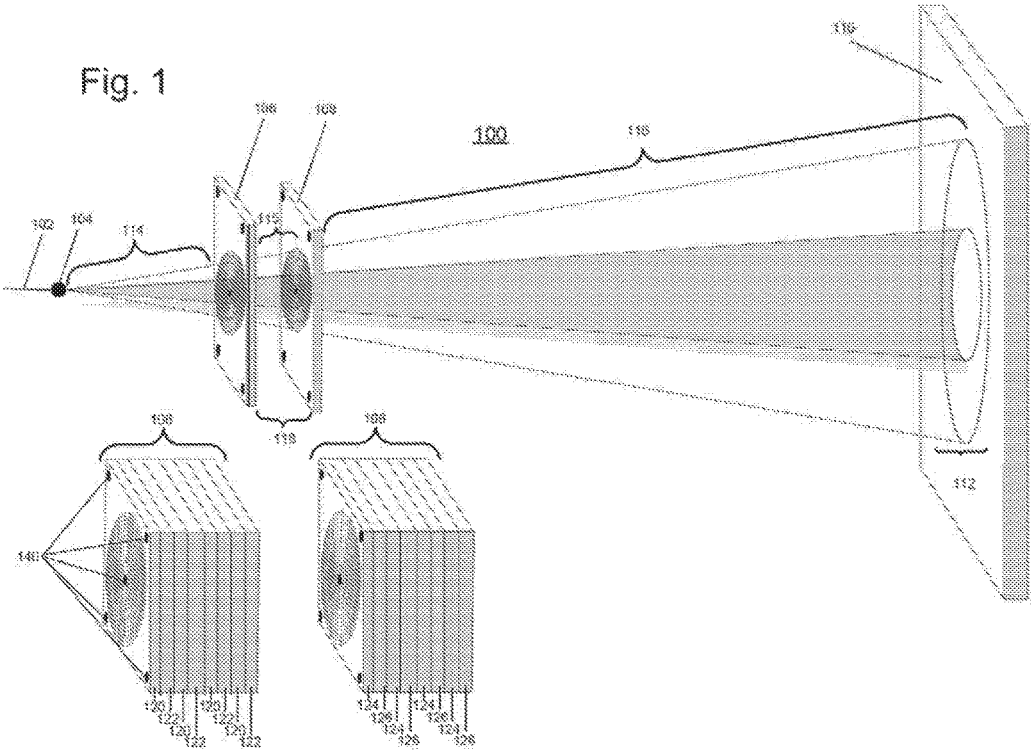




Fig. 3

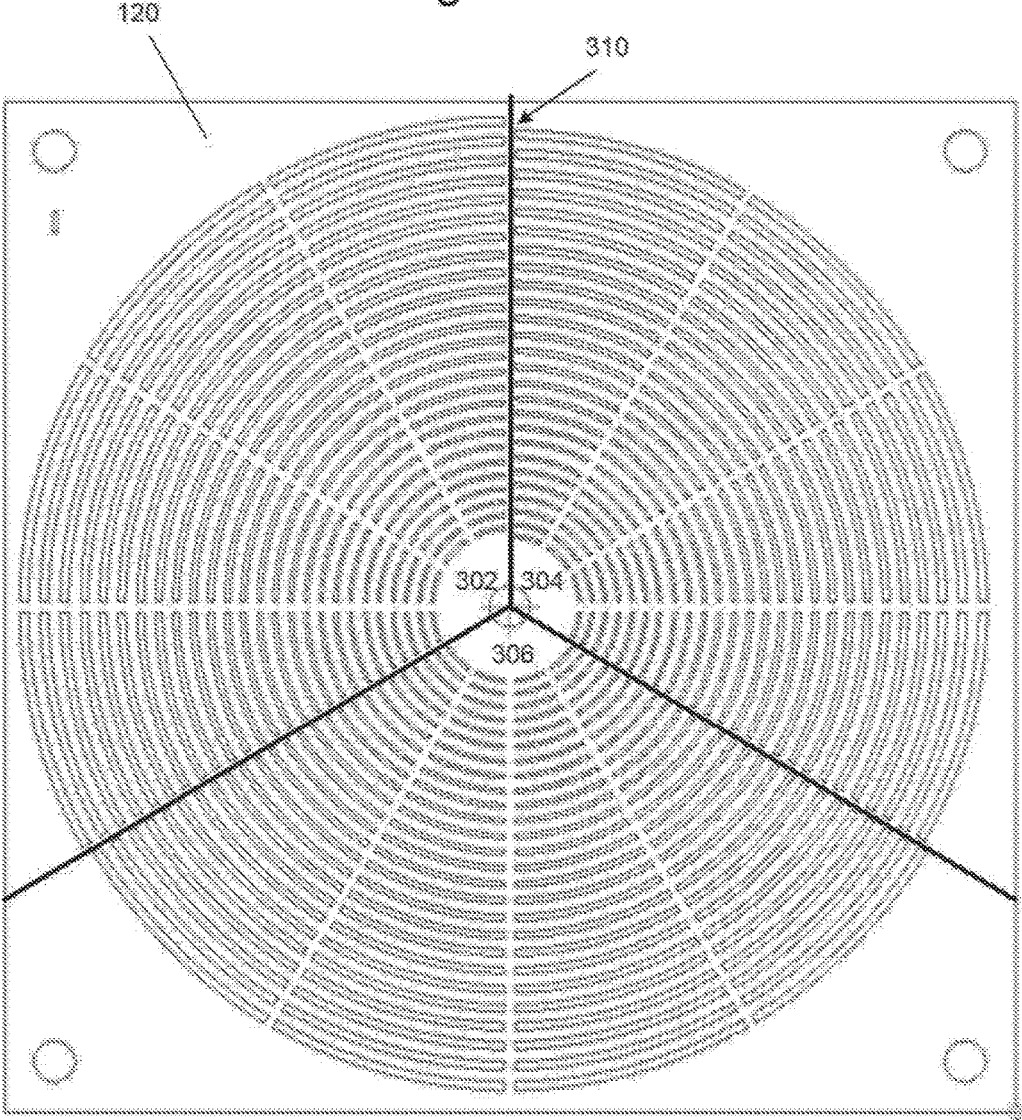


Fig. 4

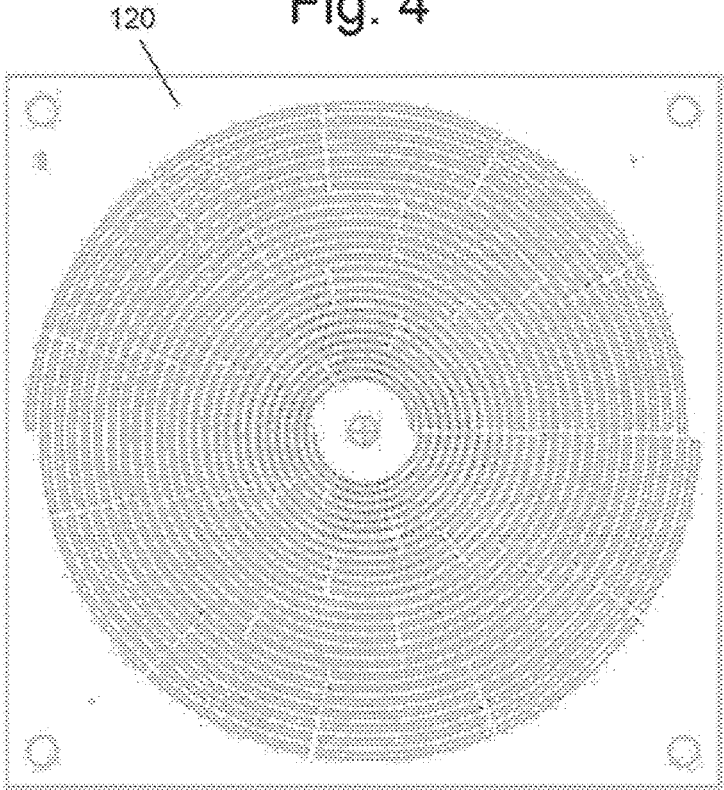


Fig. 5

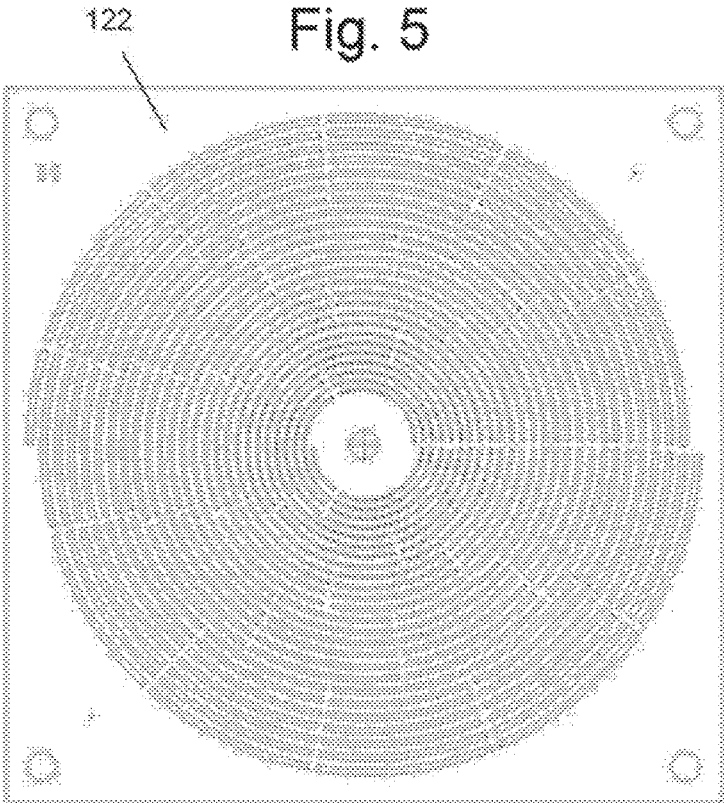


Fig. 6

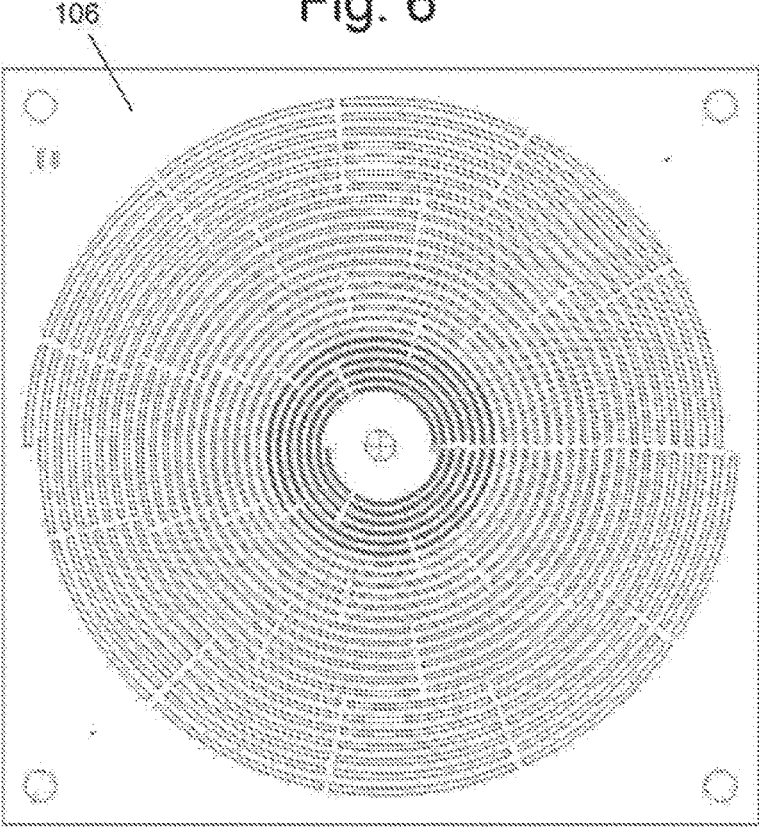


Fig. 7

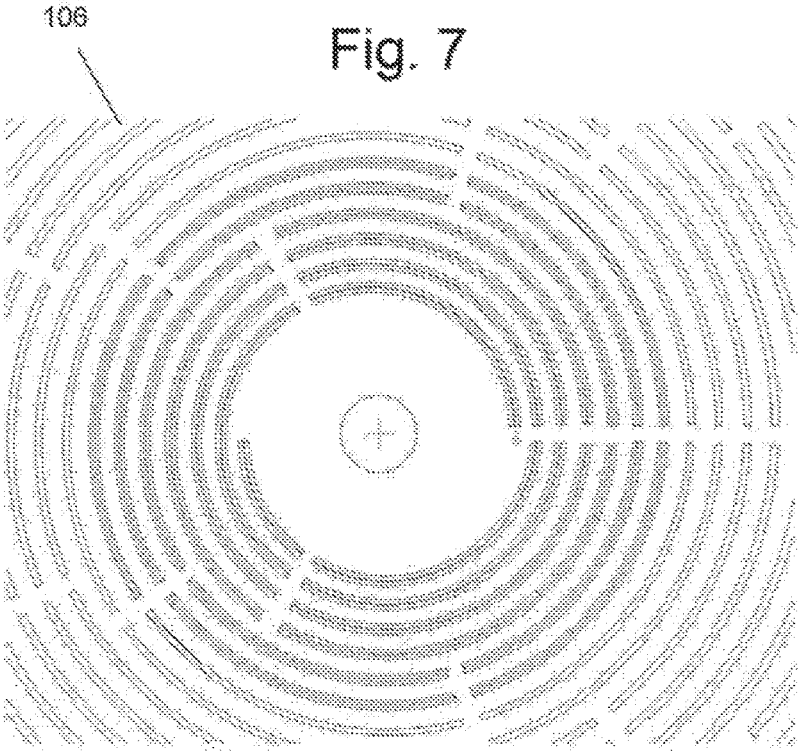
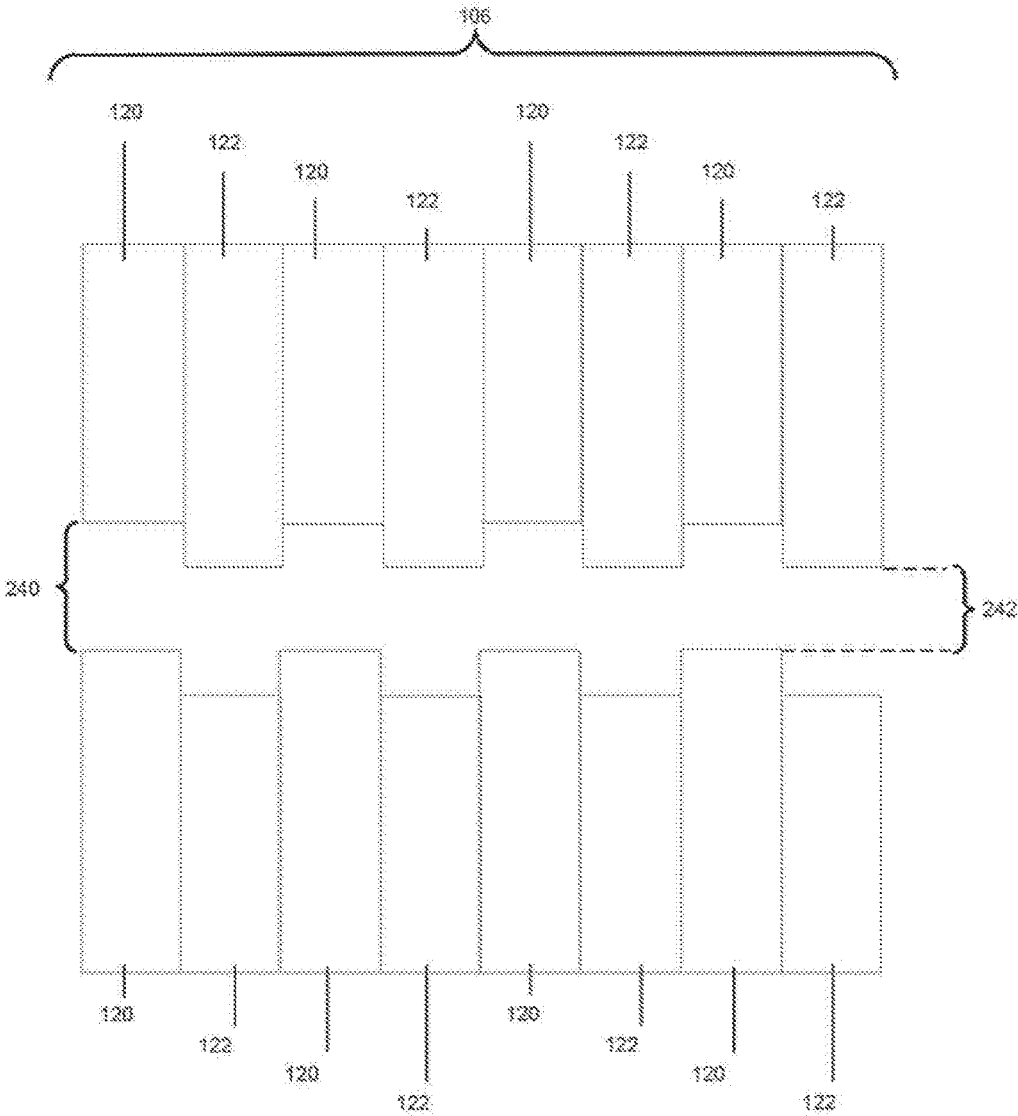
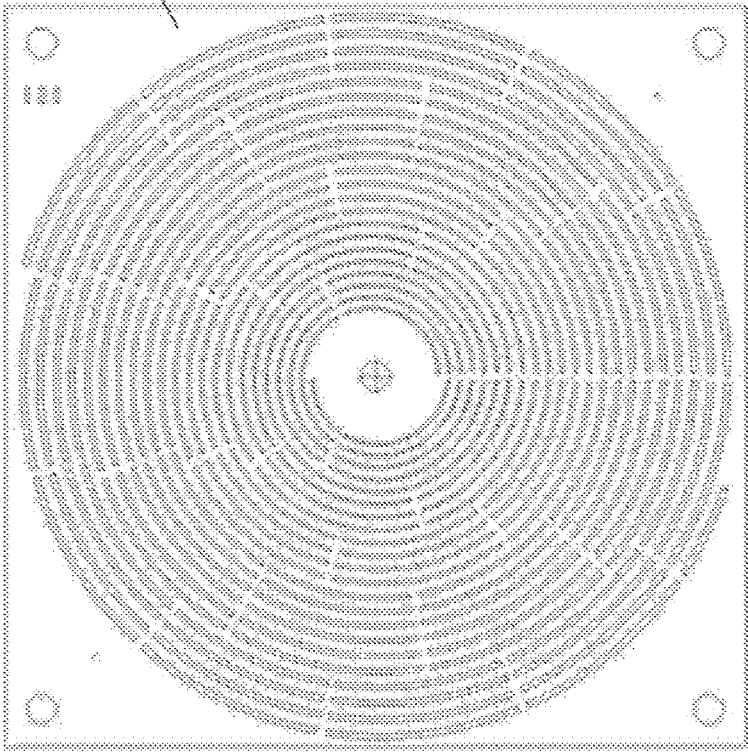


Fig. 8



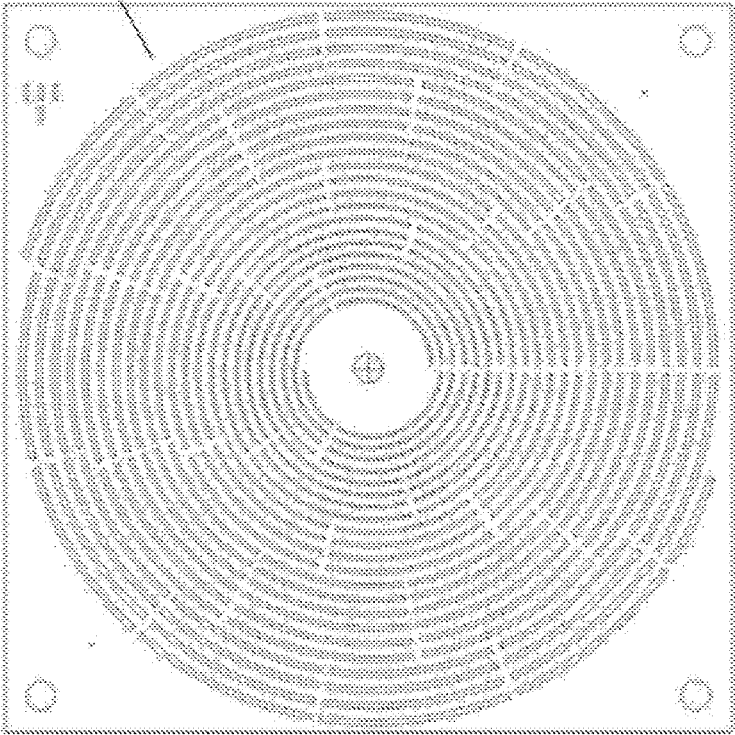
124

Fig. 9



126

Fig. 10





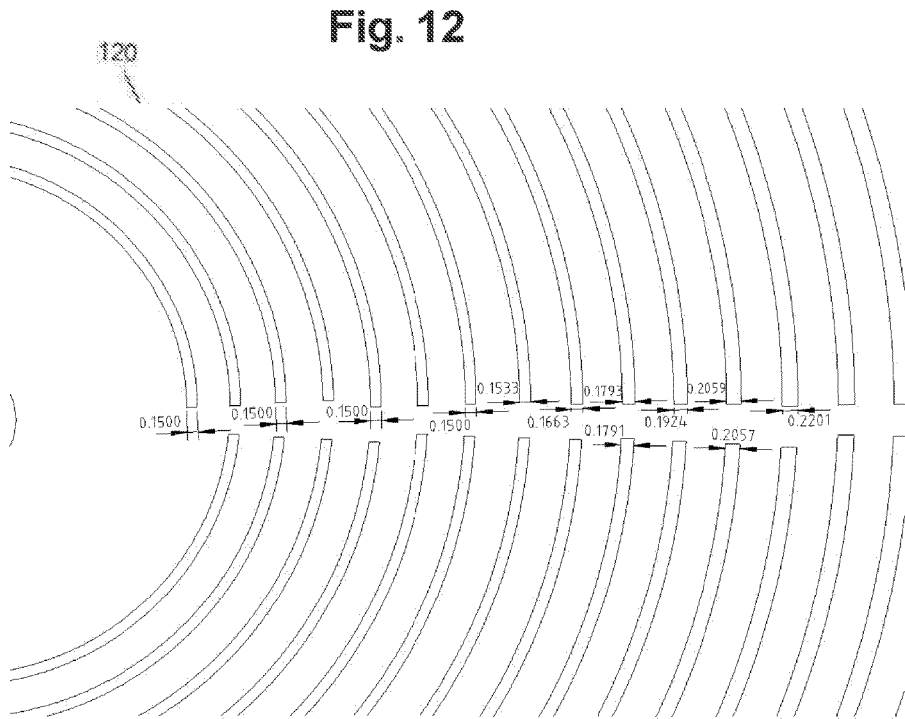
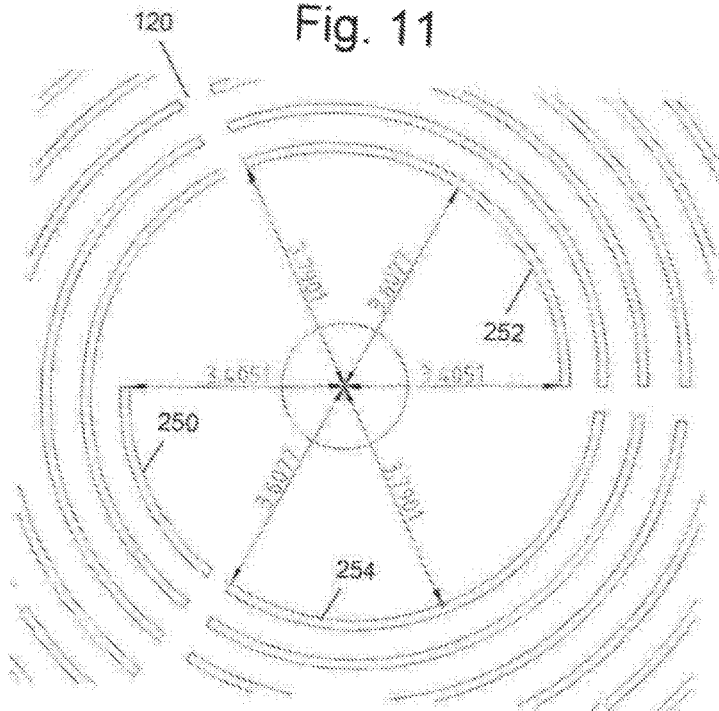
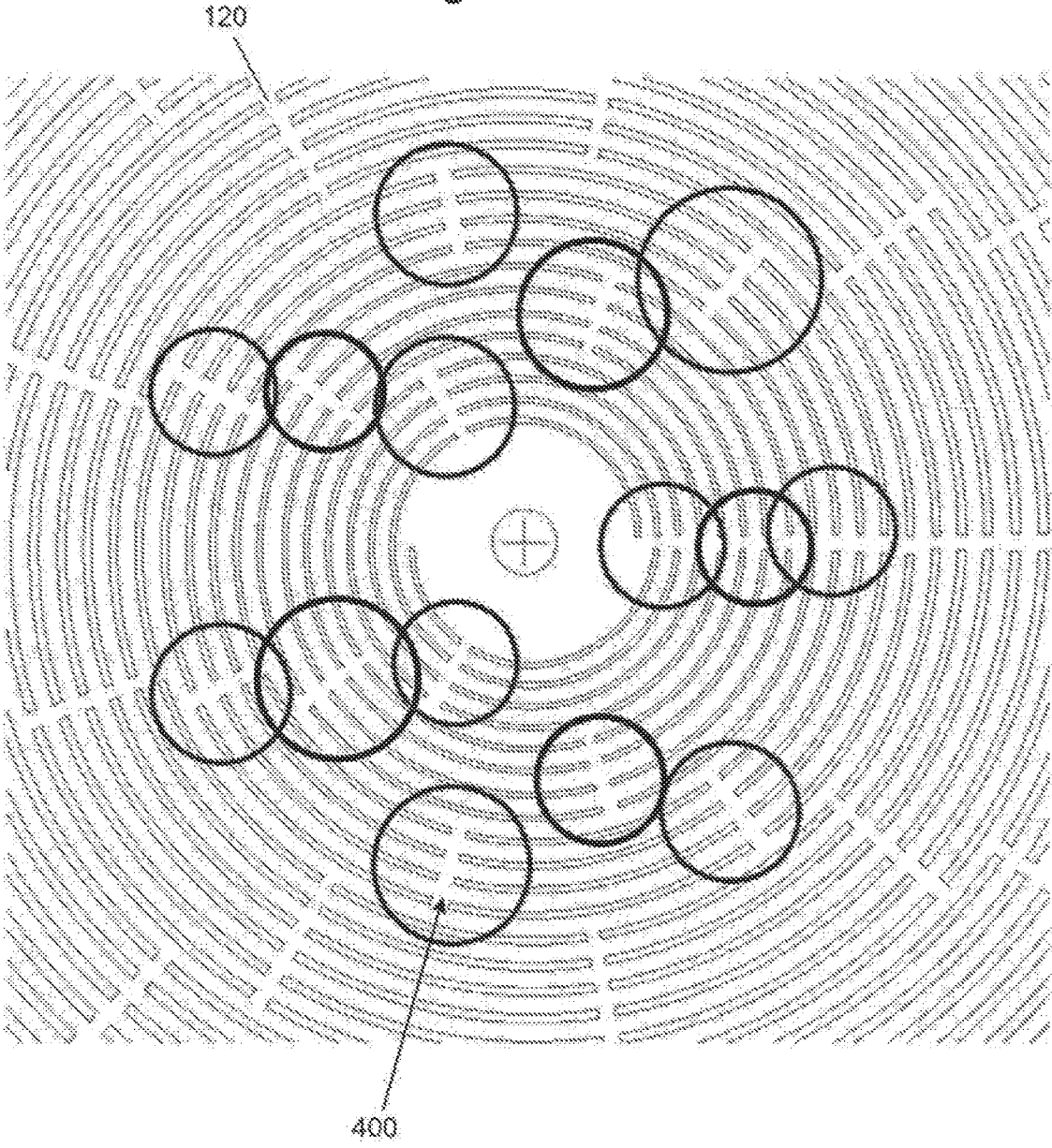


Fig. 13



## X-RAY FILTER FOR X-RAY POWDER DIFFRACTION

### CROSS-REFERENCE TO A RELATED APPLICATION

This application is a continuation of U.S. application Ser. No. 14/955,404, filed Dec. 1, 2015 which claims the benefit under 35 U.S.C. 119(e) of U.S. Provisional Application No. 62/085,870 filed on Dec. 1, 2014 each of which the contents are incorporated herein in its entirety.

The present application was made with government support under contract number DE-AC02-98CH10886 and DE-SC0012704 awarded by the U.S. Department of Energy. The United States government has certain rights in the invention(s).

### FIELD OF THE INVENTION

This disclosure relates generally to x-ray powder diffraction, a technique used for analyzing and identifying crystalline material.

### BACKGROUND

In x-ray powder diffraction, x-rays are directed at a polycrystalline sample and the diffracted x-rays are collected. The diffracted x-rays may form a diffraction pattern produced from coherently scattered x-rays by periodically spaced atoms in the sample, as described by Bragg's law of diffraction. The diffraction pattern may include information about the crystalline structure of the sample. Peaks observed in the diffraction pattern may be analyzed to identify interatomic distances within the sample.

### SUMMARY

In some examples, filters are generally described. The filters may comprise a first plate. The first plate may include an x-ray absorbing material and walls defining first slits. The first slits may include arc shaped openings through the first plate. The walls of the first plate may be configured to absorb at least some of first x-rays when the first x-rays are incident on the x-ray absorbing material, and to output second x-rays. The filters may comprise a second plate spaced from the first plate. The second plate may include the x-ray absorbing material and walls defining second slits. The second slits may include arc shaped openings through the second plate. The walls of the second plate may be configured to absorb at least some of second x-rays and to output third x-rays.

In some examples, methods to implement a filter are generally described. The methods may comprise aligning a first plate spaced from a second plate. The first plate may include an x-ray absorbing material and walls defining first slits. The walls of the first plate may be configured to absorb at least some of first x-rays when the first x-rays are incident on the x-ray absorbing material, and to output second x-rays. The second plate may include the x-ray absorbing material and walls defining second slits. The walls of the second plate may be configured to absorb at least some of second x-rays and to output third x-rays. The methods may comprise positioning the spaced first and second plates a distance from a sample. The first and second plates may be aligned a distance from the sample. The methods may further comprise directing fourth x-rays at the sample. At least some of fourth x-rays may be diffracted by the sample to produce the first x-rays.

In some examples, filter systems are generally described. The filter systems may comprise a first plate. The first plate may include an x-ray absorbing material and walls defining first slits. The first slits may include arc shaped openings through the first plate. The walls of the first plate may be configured to absorb at least some of first x-rays when the first x-rays are incident on the x-ray absorbing material, and to output second x-rays. The systems may comprise a second plate spaced from the first plate. The second plate may include the x-ray absorbing material and walls defining second slits. The second slits may include arc shaped openings through the second plate. The walls of the second plate may be configured to absorb at least some of second x-rays and to output third x-rays. The system may comprise an area detector positioned so as to receive the third x-rays. The system may further comprise an x-ray source configured to direct fourth x-rays at a sample. At least some of fourth x-rays may be diffracted by the sample to produce the first x-rays.

The foregoing summary is illustrative only and is not intended to be in any way limiting. In addition to the illustrative aspects, embodiments, and features described above, further aspects, embodiments, and features will become apparent by reference to the drawings and the following detailed description.

### BRIEF DESCRIPTION OF THE FIGURES

The foregoing and other features of this disclosure will become more fully apparent from the following description and appended claims, taken in conjunction with the accompanying drawings. Understanding that these drawings depict only several embodiments in accordance with the disclosure and are, therefore, not to be considered limiting of its scope, the disclosure will be described with additional specificity and detail through use of the accompanying drawings, in which:

FIG. 1 illustrates an example system for filtering x-rays in x-ray powder diffraction utilizing plates with slits in a spider web design;

FIG. 2 is a side view for an example system for x-ray powder diffraction utilizing plates with slits in a spider web design;

FIG. 3 is a front view of an example of a three section spider web design for slits defined by walls in a plate;

FIG. 4 is a front view of an example of a spider web spiral design for slits defined by walls in a plate;

FIG. 5 is a front view of an example of a spider web spiral design for slits defined by walls in a plate;

FIG. 6 is a front view of an example of a first plate with slits in a first spider web spiral design overlapping a second plate with slits in a second spider web spiral design;

FIG. 7 is a front close-up view of an example of a first plate with slits in a first spider web spiral design overlapping a second plate with slits in a second spider web spiral design;

FIG. 8 is a cross-sectional view of a stack of plates showing an effective slit width resulting from staggered slit locations in spider web designs of alternating plates;

FIG. 9 is a front view of an example of a spider web spiral design for slits defined by walls in a plate;

FIG. 10 is a front view of an example of a spider web spiral design for slits in a plate;

FIG. 11 is a close-up front view of a plate showing distances between slits and the center of a plate;

FIG. 12 is a close-up front view of a plate showing slit width in an example spider web spiral design; and

FIG. 13 is a close-up front view of a plate showing a support structure in the plate;

all arranged according to at least some embodiments described herein.

#### DETAILED DESCRIPTION

In the following detailed description, reference is made to the accompanying drawings, which form a part hereof. In the drawings, similar symbols typically identify similar components, unless context dictates otherwise. The illustrative embodiments described in the detailed description, drawings, and claims are not meant to be limiting. Other embodiments may be utilized, and other changes may be made, without departing from the spirit or scope of the subject matter presented herein. It will be readily understood that the aspects of the present disclosure, as generally described herein, and illustrated in the Figures, can be arranged, substituted, combined, separated, and designed in a wide variety of different configurations, all of which are explicitly contemplated herein.

As used herein, any compound, material or substance which is expressly or implicitly disclosed in the specification and/or recited in a claim as belonging to a group or structurally, compositionally and/or functionally related compounds, materials or substances, includes individual representatives of the group and all combinations thereof.

FIG. 1 illustrates an example system 100 for filtering x-rays in x-ray powder diffraction utilizing plates with slits in a spider web design, arranged in accordance with at least some embodiments presented herein. As discussed in more detail below, plates with slits in a spider web design or spider web slits formed by such plates may be utilized to perform filtering of x-rays in x-ray powder diffraction.

System 100 may receive an x-ray beam 102 and a sample 104. System 100 may include a first stack of plates 106, a second stack of plates 108, and an area detector 110. First stack of plates 106 and second stack of plates 108 may be square from a front perspective. First stack of plates 106 and second stack of plates 108 may include walls which define slits or small arc shaped openings through first stack of plates 106 or through second stack of plates 108, respectively. Each slit may have a length associated with a longer arc length of the arc shaped opening and a width associated with a shorter radial width of the arc shaped opening. As described in more detail below, when viewed from a front perspective, slits defined by walls of first stack of plates 106 and walls of second stack of plates 108 may appear in a circular, spider web design or pattern. Slits defined by walls of first stack of plates 106 and walls of second stack of plates 108 may extend from about the center of first stack of plates 106 or second stack of plates 108 to the outer edges of first stack of plates 106 or second stack of plates 108.

X-ray beam 102 may be generated by an x-ray source such as a cathode tube or any other x-ray generating technique. X-ray beam 102 may be 1 keV to 120 keV, 30 keV to 120 keV, 30 keV to 100 keV, or 40 keV to 70 keV x-rays (energy range). In an example, x-ray beam 102 may be directed at sample 104. X-ray beam 102 may be diffracted upon incidence with sample 104 forming a diffraction cone 114. Diffraction cone 114 may be filtered upon incidence with first stack of plates 106 and second stack of plates 108 and output filtered diffraction cone 116. A diffraction pattern 112 may be detected by area detector 110 upon incidence from filtered diffraction cone 116.

Sample 104 may be a material to be analyzed. Sample 104 may include multiple materials of which only one material

is to be analyzed. The one material to be analyzed may be within a region of interest or a gauge volume of sample 104. Sample 104 may be a composite material such as, for example, a battery encased in steel. A user of system 100 may want to analyze electrolytes within the steel encasing of the battery. X-ray beam 102 may diffract upon incidence with the steel casing of the battery as well as upon incidence with the electrolyte within the steel casing of the battery forming diffraction cone 114. Diffraction pattern 112, detected by area detector 110 upon incidence of diffraction cone 114, may be scattered and a desired diffraction pattern for the electrolyte may not be detected due to the scattering from the diffraction upon incidence with the steel casing. As explained in more detail below, first stack of plates 106 and second stack of plates 108 may block or filter a portion of diffraction cone 114 and segregate a diffraction cone from a gauge volume of sample 104 (filtered diffraction cone 116) to be sent to area detector 110.

First stack of plates 106 and second stack of plates 108 may include stacks of plates arranged together surface to surface. First stack of plates 106 may include alternating plates 120 and 122 aligned surface to surface. As described in more detail below, first stack of plates 106 may include a plurality of alternating plates, for example, a total of eight alternating plates 120 and 122. Plates 120 and 122 may include walls which define arc shaped openings or slits through plate 120 or plate 122. Arc shaped openings or slits in alternating plates 120 and 122 may define stack slits in first stack of plates 106. Arc shaped openings or slits in alternating plates 120 and 122 may align when plates 120 and 122 are aligned surface to surface. Arc shaped openings or slits in alternating plates 120 and 122 may overlap when plates 120 and 122 are aligned surface to surface. As described in more detail below, overlapped arc shaped openings or slits in aligned plates 120 and 122 may define stack slits in stack of plates 106 with an effective arc shaped opening smaller than the arc shaped openings in plate 120 and plate 122.

Second stack of plates 108 may include alternating plates 124 and 126 aligned surface to surface. Second stack of plates 108 may include a plurality of alternating plates, for example, a total of eight alternating plates 124 and 126. Plates 124 and 126 may include walls which define arc shaped openings or slits through plate 124 or plate 126. Arc shaped openings or slits in alternating plates 124 and 126 may define stack slits in second stack of plates 108. Arc shaped openings or slits in alternating plates 124 and 126 may align when plates 124 and 126 are aligned surface to surface. Arc shaped openings or slits in alternating plates 124 and 126 may overlap when plates 124 and 126 are aligned surface to surface. As described in more detail below, overlapped arc shaped openings or slits in aligned plates 124 and 126 may define stack slits in stack of plates 108 with an effective arc shaped opening smaller than the arc shaped openings in plate 124 and plate 126.

Plates 120, 122, 124 and 126 may include an x-ray absorbing material, such as a high electron density material, for example, tungsten, gold, silver, palladium, rhodium, osmium, platinum, tantalum, lead, molybdenum or iridium, or combinations thereof. Plates 120, 122, 124 and 126 may each be 50 mm×50 mm×0.25 mm thick. First and second stacks of plates may be 50 mm×50 mm×2 mm thick. Walls of plates 120, 122, 124, and 126 may be micromachined to define arc shaped openings. Walls of plates 120, 122, 124, and 126 may define multiple arc shaped openings. Walls of plates 120, 122, 124, and 126 may define multiple arc shaped openings in specific spider web designs or patterns.

Arc shaped openings in plates **120**, **122**, **124**, and **126** or first and second stacks of plates **106**, **108** may be filled with an x-ray transparent material for a given x-ray energy. For example arc shaped openings may be filled with silicon and may be transparent to 60 keV x-rays. Walls of plates **120**, **122**, **124**, and **126** may also define five machined holes **140** respectively; one located through a center of each plate and four located at equivalent distances from each corner of each respective plate. Straight dowels may be placed through holes in plates **120** and **122** to align plates **120** and **122** in first stack of plates **106**. Straight dowels may be placed in holes in plates **124** and **126** to align plates **124** and **126** in second stack of plates **108**. Straight dowels may be placed in holes in plates **120**, **122**, **124**, and **126** to align first stack of plates **106** with second stack of plates **108**.

First stack of plates **106** and second stack of plates **108** may be aligned. Second stack of plates **108** may be arranged together surface to surface with the first stack of plates **106** or may be spaced a distance **118** from first stack of plates **106**. When second stack of plates **108** is surface to surface with the first stack of plates **106**, the distance may be for clarity, 0 mm. When second stack of plates **108** and first stack of plates **106** are spaced, the distance **118** may be based on a detector size or a function of an energy beam in a detector and may be from about 1 mm to about 50 mm, 5 mm to about 50 mm, or about 20 mm. As described in more detail below, slits in first stack of plates **106** may filter diffraction cone **114** as diffraction cone **114** is incident on first stack of plates **106** and output filtered diffraction cone **115**. Slits in second stack of plates **108** may filter filtered diffraction cone **115** as diffraction cone **115** is incident on second stack of plates **108** and output filtered diffraction cone **116**.

FIG. 2 is a side view of system **100** for x-ray powder diffraction utilizing plates with slits in a spider web design arranged in accordance with at least some embodiments presented herein. Those components in FIG. 2 that are labeled identically to components of FIG. 1 will not be described again for the purposes of clarity.

Sample **104** may comprise a first material **202** and a second material **204**. X-ray beam **102** may diffract upon incidence with sample **104** including material **202** and material **204**. A first portion of x-ray beam **102** may diffract at a first angle **216** upon incidence with material **202**. A second portion of x-ray beam **102** may diffract at a second angle **218** when incident upon material **204**. A first portion of x-ray beam **102** may diffract upon incidence with material **202** resulting in diffracted x-ray beam **220**. The second portion of x-ray beam **102** may diffract upon incidence with material **204** resulting in diffracted x-ray beam **222**.

First stack of plates **106** may filter diffraction cone **114** as diffraction cone **114** is incident on first stack of plates **106**. Diffraction cone **114** may include diffracted x-ray beam **220** and diffracted x-ray beam **222**. Slits in first stack of plates **106** may align with diffracted x-ray beam **220**, and diffracted x-ray beam **220** may pass through slits in first stack of plates **106**. Diffracted x-ray beam **220** may not be absorbed by x-ray absorbing material of first stack of plates **106**. Slits in first stack of plates **106** may not align with diffracted x-ray beam **222**. Diffracted x-ray beam **222** or a portion of diffracted **222** may be absorbed x-ray absorbing material of first stack of plates **106**. First stack of plates **106** may absorb or filter a portion of diffraction cone **114**, such as absorbing a portion of diffracted x-ray beam **222**, and output filtered diffraction cone **115**. Filtered diffraction cone **115** may include diffracted x-ray beam **220** and a portion of diffracted x-ray beam **222** not absorbed by first stack of plates **106**.

Second stack of plates **108** may be aligned with first stack of plates **106** and filtered diffraction cone **115** may be incident on second stack of plates **108**.

Second stack of plates **108** may filter filtered diffraction cone **115**. Filtered diffraction cone **115** may include diffracted x-ray beam **220** and a portion of diffracted x-ray beam **222**. Slits in second stack of plates **108** may align with diffracted x-ray beam **220**. Diffracted x-ray beam **220** may not be absorbed by x-ray absorbing material of second stack of plates **108**. Slits in second stack of plates **108** may not align with a portion of diffracted x-ray beam **222**. The portion of diffracted x-ray beam **222** may be absorbed by x-ray absorbing material of second stack of plates **108**. Second stack of plates **108** may absorb or filter a portion of filtered diffraction cone **115**, such as absorbing the portion of diffracted x-ray beam **222**, and output filtered diffraction cone **116**. Filtered diffraction cone **116** may include diffracted x-ray beam **220**.

First stack of plates **106** and second stack of plates **108** may be configured to absorb diffracted x-rays **222** from material **204** of sample **104** while not absorbing diffracted x-rays **220** diffracted from a gauge volume or region of interest of material **202** of sample **104**. First stack of plates **106** may be set a distance **210** from the gauge volume or region of interest of sample **104**. Distance **210** may be from about 25 mm to about 175 mm, or about 100 mm. Second stack of plates **108** may be spaced a distance **118** from first stack of plates **106**. Distance **118** may be from about 5 mm to about 50 mm, or about 20 mm. Diffracted x-ray beam **220** may be from a gauge volume or region of interest over an angular diffraction range of from 2 degrees to 10 degrees. Filtered diffracted x-ray beam **220** may pass through first stack of plates **106** and second stack of plates **108** to area detector **110**. First stack of plates **106** and second stack of plates **108** may be mounted and aligned on a holder **260**. Holder **260** may include five motors, one motor in each of the x, y, and z direction and two motors for rotation. Holder **260** may align first stack of plates **106** and second stack of plates **108** with sample **104** and detector **110**.

FIG. 3 is a front view of an example of a three section spider web design for slits defined by walls in plate **120**, arranged in accordance with at least some embodiments presented herein. A three section spider web design may divide plate **120** into sections **302**, **304**, and **306**. Sections **302**, **304**, and **306** may each include a set of slits in plate **120** respectively. Sections **302**, **304**, and **306** may include slits whose lengths define arcs which are offset from one another. For example, as shown at **310**, section **302** may include slits in plate **120** which are offset from slits in plate **120** in section **304**. Slits in sections **302**, **304**, and **306** may increase in size (length and width) of the arc shaped opening when viewed radially outward from the center of plate **120**. Slits in plate **120**, divided into sections **302**, **304** and **306** by a three section spider web design, may allow part of a diffraction cone to pass through plate **120** at least one of section **302**, **304**, or **306**. Use of three sections may allow for one third of a diffraction cone to pass through any one of the defined sections.

FIG. 4 is a front view of an example of a spider web spiral design for slits defined by walls in plate **120**, arranged in accordance with at least some embodiments presented herein. As previously described, each slit in plate **120** may have a length associated with a longer arc length of the arc shaped opening and a width associated with a shorter radial width of the arc shaped opening. The spider web spiral design may include slits starting from about the center of plate **120** arcing radially. A placement of the slits may result

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in a distance from the width of each subsequent slit to the center of plate **120** to increase. The continuous increase in a distance between the width of the slit and the center of plate **120**, as well as the increase in distance continuing in subsequent slits may produce a spiral design. Each time the spiral completes 360 degrees around plate **120**, the distance between the width of a subsequent slit and the center of plate **120** may increase by a width of a previous slit. Likewise, the width of a slit may continuously increase along the spiral as the distance between the width of the spiral and the center of plate **120** increases, with the exception of the innermost 5-7 rows of the spiral all including slits with a minimum slit width.

FIG. **5** is a front view of an example of a spider web spiral design for slits defined by walls in plate **122**, arranged in accordance with at least some embodiments presented herein. The spider web spiral design may include slits starting from about the center of plate **122** arcing radially. A placement of the slits may result in a distance from the width of each subsequent slit to the center of plate **122** to increase. The continuous increase in a distance between the width of the slit and the center of plate **122**, as well as the increase in distance continuing in subsequent slits may produce a spiral design. Each time the spiral completes 360 degrees around plate **122**, the distance between the width of a subsequent slit and the center of plate **122** may increase by a width of a previous slit. Likewise, the width of a slit may continuously increase along the spiral as the distance between the width of the spiral and the center of plate **122** increases, with the exception of the innermost 5-7 rows of the spiral all including slits with a minimum slit width. Plate **122** may alternate with plate **120** in a stack of eight alternating plates to form first stack of plates **106**. As shown in more detail below, slits in the innermost 5-7 rows of the spiral in plate **120** may overlap slits in innermost 5-7 rows of the spiral in plate **122** to create a smaller effective width.

FIG. **6** is a front view of a first stack of plates **106** with an example of plate **120** with slits in a spider web spiral design overlapping plate **122** with slits in a second spider web spiral design, arranged in accordance with at least some embodiments presented herein. FIG. **7** is a front close-up view of a first stack of plates **106** with an example plate **120** with slits in a spider web spiral design overlapping plate **122** with slits in a second spider web spiral design, arranged in accordance with at least some embodiments presented herein. As shown in FIG. **6** and FIG. **7** the slits in the innermost 5-7 rows of the spiral in plate **120** may be designed to be staggered from the slits in innermost 5-7 rows of the spiral in plate **122**. The slits in the innermost 5-7 rows of the spiral in plate **120** may overlap the slits in the innermost 5-7 rows of spiral in plate **122** when plates **120** and **122** are aligned and stacked in first stack of plates **106**. The overlap may create a smaller effective width to the slits in the innermost 5-7 rows of the spiral in first stack of plates **106**. For example, it may be desired to obtain innermost slits with widths of about 90 microns, but a laser micromachining process may be limited to producing a slit with a width of about 150 microns. Staggering or offsetting slits with a width of about 150 microns by about 60 microns in first stack of plates **106** may result in an effective slit width of about 90 microns. Effective slit widths for first stack of plates **106** and second stack of plates **108** may range from about 1 micron to about 500 microns.

FIG. **8** is a cross-sectional view of first stack of plates **106** showing an effective slit width resulting from staggered slit locations in spider web designs of alternating plates, arranged in accordance with at least some embodiments

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presented herein. First stack of plates **106** may include eight stacked and aligned alternating plates **120** and **122**. The innermost slits defined by wall in plate **120** and the innermost slits defined by walls in plate **122** may be a process limiting width **240**. The innermost slits in plate **120** may be designed, such as by a spider web design, to overlap the innermost slits in plate **122** when plates **120** and **122** are aligned and stacked. The overlap in the innermost slits in plate **120** and **122** may create a smaller effective stack slit width **242** for first stack of plates **106**.

FIG. **9** is a front view of an example of a spider web spiral design for slits defined by walls in plate **124**, arranged in accordance with at least some embodiments presented herein. The spider web spiral design may include slits starting from about the center of plate **124** arcing radially. A placement of the slits may result in a distance from the width of each slit from the center of plate **124** to increase. The continuous increase in a distance between the width of the slit and the center of plate **124**, as well as the increase in distance continuing in subsequent slits may produce a spiral design. Each time the spiral completes 360 degrees around plate **124**, the distance between the width of a subsequent slit and the center of plate **124** may increase by a width of a previous slit. The width of a slit may continuously increase along the spiral as the distance between the width of the spiral and the center of plate **124** increases, with the exception of the innermost 5-7 rows of the spiral all including slits with a minimum slit width.

FIG. **10** is a front view of an example of a spider web spiral design for slits defined by walls in plate **126**, arranged in accordance with at least some embodiments presented herein. The spider web spiral design may include slits starting from about the center of plate **126** arcing radially. A placement of the slits may result in a distance from the width of each slit from the center of plate **126** to increase. The continuous increase in a distance between the width of the slit and the center of plate **126**, as well as the increase in distance continuing in subsequent slits may produce a spiral design. Each time the spiral curve completes 360 degrees around plate **126**, the distance between the width of a subsequent slit and the center of plate **126** may increase by a width of a previous slit. The width of a slit may continuously increase along the spiral as the distance between the width of the spiral and the center of plate **126** increases, with the exception of the innermost 5-7 rows of the spiral all including slits with a limited minimum slit width. Plate **126** may alternate with plate **124** in a stack of eight alternating plates to form second stack of plates **108**. In one example, first stack of plates includes twenty-six rows of slits and second stack of plates **108** includes twenty-two rows of slits.

FIG. **11** is a close-up front view of plate **120** showing distances between slits and the center of plate **120**, arranged in accordance with at least some embodiments presented herein. As shown in FIG. **11**, slits **250** and **252** are closest to the center of plate **120** at a first end a distance of 3.4051 mm from the center of plate **120**. As slits **250** and **252** spiral counterclockwise slits **250** and **252** may increase in distance from the center of plate **120**. As shown, slit **252** is a distance of 3.6077 mm from the center of plate **120** at about the midpoint of slit **252**, and 3.7901 mm from the center of plate **120** at a second end counterclockwise from the first end. Slit **254** is a subsequent slit to slit **250** and is closest to the center of plate **120** at a first end with a distance of 3.6077 mm. Slit **254** increases in distance from the center of plate **120** to 3.7901 mm at about the midpoint of slit **254**. Subsequent slits may continually increase in distance from the center of plate **120** as the subsequent slits spiral counterclockwise.

FIG. 11 also illustrates spiral design symmetry as a first spiral caused by slit 250, slit 254 and subsequent slits and a second spiral caused by slit 252 and subsequent slits display 2-fold rotational symmetry.

FIG. 12 is a close-up front view of plate 120 showing slit width in an example spider web spiral design, arranged in accordance with at least some embodiments presented herein. As shown in FIG. 12, the first 5-7 rows of slits closest to the center of plate 120 may have a slit width of 0.15 mm or 150 microns with slit width of subsequent slits increasing with distance from the center of plate 120.

FIG. 13 is a close-up front view of plate 120 showing support structure in plate 120, arranged in accordance with at least some embodiments presented herein. Plate 120 may include walls defining slits in a spiral design. A slit designed as a continuous spiral running counter-clockwise from a center of plate 120 to an outer edge of plate 120 may compromise the integrity and structure of plate 120. Support structures 400 interrupting a continuous spiral may be arranged at specific locations to provide structural integrity to plate 120. Support structures 400 may be designed or patterned to include odd fold symmetry, such as 3-fold or 5-fold symmetry, so that when a support is on one side of plate 120 there is not a support 180 degrees on the other side of plate 120. First stack of plates 106 and second stack of plates 108 may be rotated about a central axis of x-rays directed at first stack of plates 106 so as to detect a full diffraction cone and minimize x-rays absorbed by structural supports 400. An x-ray diffraction detector may record a long exposure, over a set time period or over an integer number of revolutions in a set time period to capture information related to an entire diffraction cone.

Among other possible benefits, a system in accordance with the present disclosure may produce higher resolution diffraction cones making for more accurate analysis. The present disclosure may measure part of a diffraction cone from a particular gauge volume of a sample over an angular range of 2 degrees to 10 degrees and may make the apparatus more versatile because its gauge volume selection is not limited to just a select few angles. The apparatus may also collect data more rapidly. A system in accordance with

the present disclosure may also reduce background diffraction from sample containers, reaction cell windows, or pressure cell windows.

While various aspects and embodiments have been disclosed herein, other aspects and embodiments will be apparent to those skilled in the art. The various aspects and embodiments disclosed herein are for purposes of illustration and are not intended to be limiting, with the true scope and spirit being indicated by the following claims.

The invention claimed is:

1. A filter system comprising:

a first plate, wherein the first plate includes a center, an x-ray absorbing material and walls defining first slits, wherein the first slits include arc shaped openings through the first plate starting from the center and wherein the arc shaped openings arc radially from the center, form a spiral, and are staggered when viewed radially from respective centers of respective plates, the walls of the first plate configured to absorb at least some of first x-rays when the first x-rays are incident on the x-ray absorbing material, and to output second x-rays;

and a second plate spaced from the first plate, wherein the second plate includes the x-ray absorbing material and walls defining second slits, wherein the second slits include arc shaped openings through the second plate, the walls of the second plate configured to absorb at least some of second x-rays and to output third x-rays; an area detector positioned so as to receive the third x-rays;

and an x-ray source configured to direct fourth x-rays at a sample, such that at least some of fourth x-rays are diffracted by the sample to produce the first x-rays;

and a motor configured to rotate the first and second plates about a central axis of the fourth x-rays.

2. The filter system of claim 1, wherein the first slits further include two sections of slits offset from one another.

3. The filter system of claim 1, wherein the first plate further includes a support structure arranged to include odd fold symmetry.

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